

Search Notes**Application/Control No.**

10/050,123

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2638

SEARCHED

Class	Subclass	Date	Examiner
375	295	9/29/2005	JP
	146	9/29/2005	JP
	296	9/29/2005	JP
	297	9/29/2005	JP
710	8	9/29/2005	JP
375	316	2/16/2006	JP
	324	2/16/2006	JP
	325	2/16/2006	JP

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	9/29/2005	JP
Inventor Name Search East/EDAN	9/29/2005	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	316	2/16/2006	JP
	324	2/16/2006	JP
	325	2/16/2006	JP